# 2.5V/3.3V SiGe Differential Smart Gate with CML Output

The NB7L86M is a multi-function differential Logic Gate, which can be configured as an AND/NAND, OR/NOR, XOR/XNOR, or 2:1 MUX. This device is part of the GigaComm family of high performance Silicon Germanium products. The NB7L86M is an ultra-low jitter multi-logic gate with a maximum data rate of 12 Gb/s and input clock frequency of 8 GHz suitable for Data Communication Systems, Telecom Systems, Fiber Channel, and GigE applications.

The device is housed in a low profile 3x3 mm 16–pin QFN package. Differential inputs incorporate internal 50  $\Omega$  termination resistors and accept LVNECL (Negative ECL), LVPECL (Positive ECL), LVCMOS, LVTTL, CML, or LVDS. The differential 16 mA CML output provides matching internal 50  $\Omega$  termination, and 400 mV output swing when externally terminated 50  $\Omega$  to VCC.

Application notes, models, and support documentation are available on www.onsemi.com.

## **Features**

- Maximum Input Clock Frequency up to 8 GHz
- Maximum Input Data Rate up to 12 Gb/s Typical
- 30 ps Typical Rise and Fall Times
- 90 ps Typical Propagation Delay
- 2 ps Typical Within Device Skew
- CML Output with Operating Range:  $V_{CC} = 2.375 \text{ V}$  to 3.465 V with  $V_{EE} = 0 \text{ V}$
- CML Output Level (400 mV Peak-to-Peak Output) Differential Output
- 50  $\Omega$  Internal Input and Output Termination Resistors
- Functionally Compatible with Existing 2.5 V/3.3 V LVEL, LVEP, EP and SG Devices



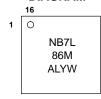
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## MARKING DIAGRAM\*



QFN-16 MN SUFFIX CASE 485G



A = Assembly Location

L = Wafer Lot

Y = Year

W = Work Week

\*For additional marking information, refer to Application Note AND8002/D.

## ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 11 of this data sheet.

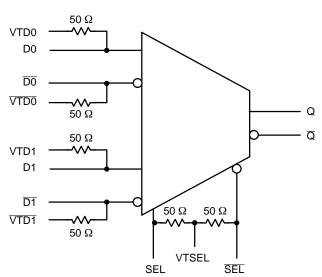


Figure 1. Simplified Logic Diagram

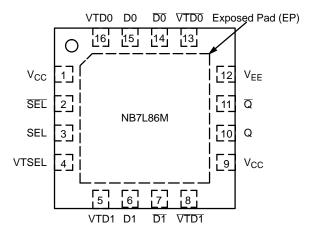


Figure 2. Pin Configuration (Top View)

# **Table 1. PIN DESCRIPTION**

Pin	Name	I/O	Description	
1, 9	V <sub>CC</sub>	Power Supply	Positive Supply Voltage. All $V_{\rm CC}$ pins must be externally connected to Power Supply to guarantee proper operation.	
2	SEL	LVPECL, CML, LVCMOS, LVTTL, LVDS Input	Inverted Differential Select Logic Input.	
3	SEL	LVPECL, CML, LVCMOS, LVTTL, LVDS Input	Non-inverted Differential Select logic Input.	
4	$V_{TSEL}$	-	Common Internal 50 $\Omega$ termination pin for SEL/SEL. See Table 6. (Note 1)	
5	$V_{TD1}$	-	Internal 50 $\Omega$ Termination Pin for D1. See Table 6. (Note 1)	
6	D1	LVPECL, CML, LVCMOS, LVTTL, LVDS Input	Non-inverted Differential Clock/Data Input D1. (Note 1)	
7	D1	LVPECL, CML, LVCMOS, LVTTL, LVDS Input	Inverted Differential Clock/Data Input $\overline{D1}$ . (Note 1)	
8	$\overline{V_{TD1}}$	-	Internal 50 $\Omega$ Termination Pin for $\overline{\text{D1}}$ . See Table 6. (Note 1)	
10	Q	CML Output	Non-inverted Output with Internal 50 $\Omega$ Source Termination Resistor. (Note 2)	
11	Q	CML Output	Inverted Output with Internal 50 $\Omega$ Source Termination Resistor. (Note 2)	
12	V <sub>EE</sub>	Power Supply	Negative Supply Voltage. All $V_{\text{EE}}$ pins must be externally connected to Power Supply to guarantee proper operation.	
13	$\overline{V_{TD0}}$	-	Internal 50 $\Omega$ Termination Pin for D0. (Note 1)	
14	D0	LVPECL, CML, LVCMOS, LVTTL, LVDS Input	Non-inverted Differential Clock/Data Input $\overline{D0}$ . (Note 1)	
15	D0	LVPECL, CML, LVCMOS, LVTTL, LVDS Input	Non-inverted differential clock/data input D0. (Note 1)	
16	V <sub>TD0</sub>	-	Internal 50 $\Omega$ Termination Pin for $\overline{D0}$ . (Note 1)	
_	EP	-	Exposed Pad. Thermal pad on the package bottom must be attached to a heatsinking conduit to improve heat transfer.	

In the differential configuration when the input termination pins (V<sub>TDx</sub>, V̄<sub>TDx</sub>) are connected to a common termination voltage or left open, and if no signal is applied on Dx and Dx then the device will be susceptible to self–oscillation.
 CML output require 50 Ω receiver termination resistor to VCC for proper operation.

D0

0

0

0

0

specified otherwise.

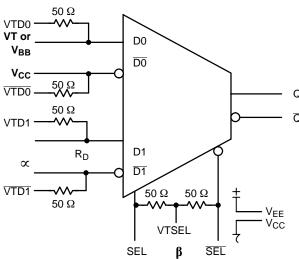


Figure 3. Configuration for AND/NAND Function

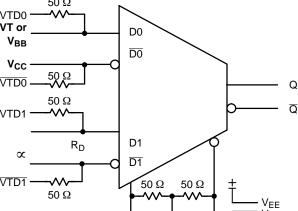


Table 3. OR/NOR TRUTH TABLE (Note 4)

Table 2. AND/NAND TRUTH TABLE (Note 3)

D1

0

0

1

1

b

SEL

0

1

0

1

DO, D1, SEL are complementary of D0, D1, SEL unless

 $\propto$  AND b

Q

0

0

0

1

Table 3. OK/NOK TROTH TABLE (Note 4)							
α		β	∝ or β				
D0	D1	SEL	Q				
0	1	0	0				
0	1	1	1				
1	1	0	1				
1	1	1	1				

4.  $\overline{D0}$ ,  $\overline{D1}$ ,  $\overline{SEL}$  are complementary of D0, D1, SEL unless specified otherwise.

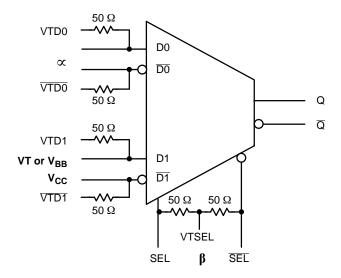


Figure 4. Configuration for OR/NOR Function

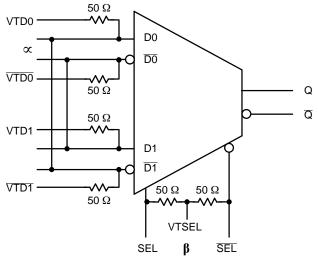


Figure 5. Configuration for XOR/XNOR Function

Table 4. XOR/XNOR TRUTH TABLE (Note 5)

α		β	∝ XOR β
D0	D1	SEL	Q
0	1	0	0
0	1	1	1
1	0	0	1
1	0	1	0

5.  $\overline{D0}$ ,  $\overline{D1}$ ,  $\overline{SEL}$  are complementary of D0, D1, SEL unless specified otherwise.

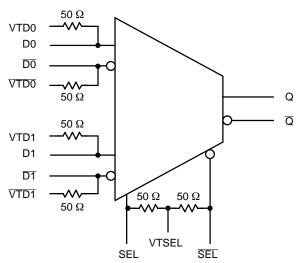


Figure 6. Configuration for 2:1 MUX Function

# Table 5. 2:1 MUX TRUTH TABLE (Note 6)

SEL	Q
1	D1
0	D0

6. D0, D1, SEL are complementary of D0, D1, SEL unless specified otherwise.

# **Table 6. ATTRIBUTES**

Characteri	Value				
ESD Protection	Human Body Model Machine Model Charged Device Model	> 1500 V > 50 V > 500 V			
Moisture Sensitivity (Note 7) QFN-16		Level 1			
Flammability Rating	Oxygen Index: 28 to 34	UL 94 V-0 @ 0.125 in			
Transistor Count	TBD				
Meets or exceeds JEDEC Spec EIA/JESD78 IC Latchup Test					

<sup>7.</sup> For additional Moisture Sensitivity information, refer to Application Note AND8003/D.

## **Table 7. MAXIMUM RATINGS**

Symbol	Parameter	Condition 1	Condition 2	Rating	Units
V <sub>CC</sub>	Positive Power Supply	V <sub>EE</sub> = 0 V		3.6	V
VI	Input Voltage	V <sub>EE</sub> = 0 V	$V_{EE} \le V_I \le V_{CC}$	3.6	V
V <sub>INPP</sub>	Differential Input Voltage  D - D	$\begin{array}{ccc} V_{CC} - V_{EE} \geq & 2.8 \ V \\ V_{CC} - V_{EE} < & 2.8 \ V \\ \end{array}$		2.8  V <sub>CC</sub> – V <sub>EE</sub>	V
I <sub>IN</sub>	Input Current Through $R_T$ (50 $\Omega$ Resistor)	Continuous Surge		25 50	mA mA
l <sub>out</sub>	Output Current	Continuous Surge		25 50	mA mA
T <sub>A</sub>	Operating Temperature Range	QFN-16		-40 to +85	°C
T <sub>stg</sub>	Storage Temperature Range			-65 to +150	°C
$\theta_{JA}$	Thermal Resistance (Junction–to–Ambient) (Note 8)	0 lfpm 500 lfpm	QFN-16 QFN-16	42 36	°C/W
$\theta_{\sf JC}$	Thermal Resistance (Junction-to-Case)	2S2P (Note 8)	QFN-16	3 to 4	°C/W
T <sub>sol</sub>	Wave Solder Pb Pb-Free	< 3 Sec @ 248°C < 3 Sec @ 260°C		265 265	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

8. JEDEC standard multilayer board – 2S2P (2 signal, 2 power).

Table 8. DC CHARACTERISTICS ( $V_{CC}$  = 2.375 V to 3.465 V,  $V_{EE}$  = 0 V,  $T_A$  = -40°C to +85°C)

Symbol	Characteristic		Min	Тур	Max	Unit
I <sub>CC</sub>	Power Supply Current (Inputs and Outputs Open)		20	30	40	mA
$V_{OH}$	Output HIGH Voltage (Notes 9 and 10)		V <sub>CC</sub> – 60	V <sub>CC</sub> – 30	V <sub>CC</sub>	mV
$V_{OL}$	Output LOW Voltage (Notes 9 and 10)		V <sub>CC</sub> – 460	V <sub>CC</sub> – 400	V <sub>CC</sub> – 310	mV
Differential	Input Driven Single–Ended (see Figures 16 & 18)					
$V_{th}$	Input Threshold Reference Voltage Range (Note 11)		1125		V <sub>CC</sub> – 75	mV
V <sub>IH</sub>	Single-ended Input HIGH Voltage (Note 12)		V <sub>th</sub> + 75		V <sub>CC</sub>	mV
$V_{IL}$	Single-ended Input LOW Voltage (Note 12)		V <sub>EE</sub>		V <sub>CC</sub> – 150	mV
Differential	Inputs Driven Differentially (see Figures 17 & 19)				•	
$V_{IHD}$	Differential Input HIGH Voltage		1200		V <sub>CC</sub>	mV
$V_{ILD}$	Differential Input LOW Voltage		V <sub>EE</sub>		V <sub>CC</sub> – 75	mV
$V_{CMR}$	Input Common Mode Range (Differential Configuration	on)	1163		V <sub>CC</sub> – 38	mV
$V_{ID}$	Differential Input Voltage (VIHD - VILD)		75		2500	mV
I <sub>IH</sub>	Input HIGH Current	D0/ <u>D0</u> /D1/ <u>D1</u> SEL/ <u>SEL</u>	0 –50	50 20	100 100	μΑ
I <sub>IL</sub>	Input LOW Current	D0/ <u>D0</u> /D1/ <u>D1</u> SEL/ <u>SEL</u>	0 –50	50 20	100 50	μΑ
R <sub>TIN</sub>	Internal Input Termination Resistor		45	50	55	Ω
R <sub>TOUT</sub>	Internal Output Termination Resistor		45	50	55	Ω
R <sub>Temp Coef</sub>	Internal I/O Termination Resistor Temperature Coefficient			-3.75		mΩ/°C

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

<sup>9.</sup> CML outputs require 50  $\Omega$  receiver termination resistors to  $V_{CC}$  for proper operation.

<sup>10.</sup> Input and output parameters vary 1:1 with V<sub>CC</sub>.
11. V<sub>th</sub> is applied to the complementary input when operating in single–ended mode.
12. V<sub>CMR</sub> min varies 1:1 with V<sub>CC</sub>.

Table 9. AC CHARACTERISTICS ( $V_{CC} = 2.375 \text{ V}$  to 3.465 V,  $V_{EE} = 0 \text{ V}$ ; Note 13)

Symbol	Characteristic		-40°C			25°C			85°C		Unit
		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
V <sub>OUTPP</sub>	Output Voltage Amplitude (@V <sub>INPPmin</sub> ) $f_{in} \le 4$ GHz (See Figure 7) $f_{in} \le 8$ GHz	240 125	350 230		240 125	350 230		240 125	350 230		mV
f <sub>data</sub>	Maximum Operating Data Rate	10.7	12		10.7	12		10.7	12		Gb/s
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation Delay to Dx/Dx to Q/Q Output Differential @ 1 GHz SEL/SEL to Q/Q (See Figure 7)	70 110	90 135	120 160	70 110	90 135	120 160	70 110	90 135	120 160	ps
t <sub>SKEW</sub>	Duty Cycle Skew (Note 14) Device–to–Device Skew (Note 15)		2.0 5.0	10 20		2.0 5.0	10 20		2.0 5.0	10 20	ps
<sup>t</sup> JITTER	$\begin{array}{ll} \text{RMS Random Clock Jitter (Note 16)} & f_{\text{in}} = 4 \text{ GHz} \\ & f_{\text{in}} = 8 \text{ GHz} \\ \text{Peak-to-Peak Data Dependent Jitter} & f_{\text{in}} = 4 \text{ Gb/s} \\ \text{(Note 17)} & f_{\text{in}} = 10 \text{ Gb/s} \end{array}$		0.2 0.2 4.0 4.0	0.7 0.7 10 10		0.2 0.2 4.0 4.0	0.7 0.7 10 10		0.2 0.2 4.0 4.0	0.7 0.7 10 10	ps
V <sub>INPP</sub>	Input Voltage Swing/Sensitivity (Differential Configuration) (Note 18)	75	400	2600	75	400	2600	75	400	2600	mV
t <sub>r</sub> t <sub>f</sub>	Output Rise/Fall Times @ 1 GHz Q, Q (20% – 80%)		35	60		35	60		35	60	ps

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

- 13. Measured by forcing  $V_{INPP}$  (TYP) from a 50% duty cycle clock source. All loading with an external  $R_L$  = 50  $\Omega$  to  $V_{CC}$ . Input edge rates 40 ps (20% 80%).
- 14. Duty cycle skew is measured between differential outputs using the deviations of the sum of Tpw- and Tpw+ @1 GHz.
- 15. Device to device skew is measured between outputs under identical transition @ 1 GHz.
- 16. Additive RMS jitter with 50% duty cycle clock signal at 4 GHz and 10 GHz.
- 17. Additive peak-to-peak data dependent jitter with input NRZ data (PRBS 2<sup>23</sup>-1) at 4 Gb/s and 10 Gb/s.
- 18. V<sub>INPP</sub> (MAX) cannot exceed V<sub>CC</sub> V<sub>EE</sub>. Input voltage swing is a single-ended measurement operating in differential mode.

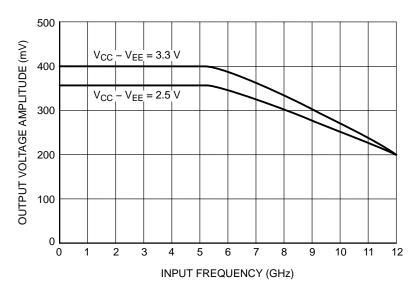


Figure 7. Output Voltage Amplitude (V<sub>OUTPP</sub>) versus Input Clock Frequency (f<sub>in</sub>) at Ambient Temperature (Typical)

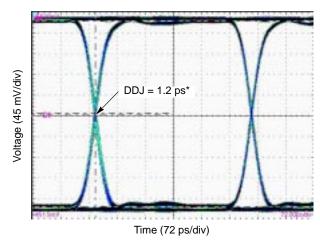


Figure 8. Typical Output Waveform at 2.488 GB/s with PRBS 2<sup>23</sup>-1 (V<sub>inpp</sub> = 75 mV)

\*Input signal DDJ = 10 ps

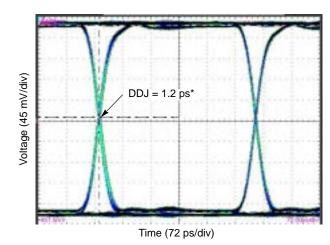


Figure 9. Typical Output Waveform at 2.488 GB/s with PRBS  $2^{^23}$ -1 ( $V_{inpp}$  = 400 mV)

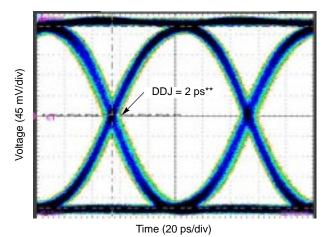


Figure 10. Typical Output Waveform at 10 GB/s with PRBS  $2^{23}-1$  ( $V_{inpp} = 75 \text{ mV}$ )

\*\*Input signal DDJ = 12 ps

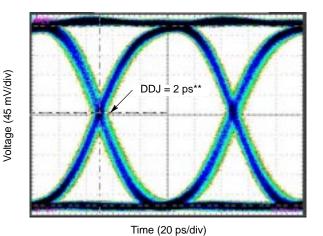


Figure 11. Typical Output Waveform at 10 GB/s with PRBS  $2^{23}$ -1 ( $V_{inpp}$  = 400 mV)

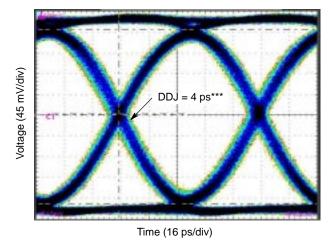


Figure 12. Typical Output Waveform at 12 GB/s with PRBS  $2^{^23}-1$  ( $V_{inpp} = 75$  mV)

\*\*\*Input signal DDJ = 14 ps

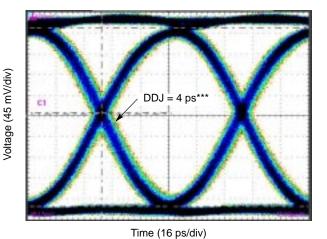


Figure 13. Typical Output Waveform at 12 GB/s with PRBS 2<sup>23</sup>-1 (V<sub>inpp</sub> = 400 mV)

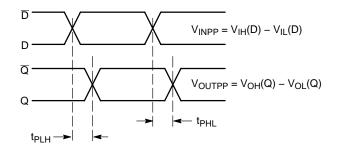


Figure 14. AC Reference Measurement

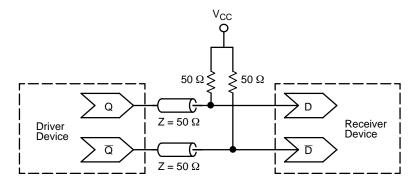


Figure 15. Typical Termination for Output Driver and Device Evaluation (Refer to Application Note AND8020 – Termination of ECL Logic Devices)

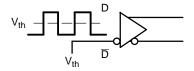


Figure 16. Differential Input Driven Single-Ended

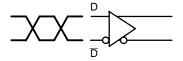


Figure 17. Differential Inputs Driven Differentially

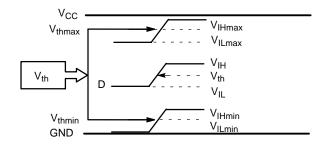


Figure 18. V<sub>th</sub> Diagram

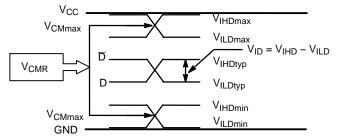


Figure 19. V<sub>CMR</sub> Diagram

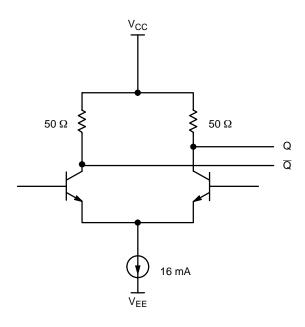


Figure 20. CML Output Structure

# **Table 10. INTERFACING OPTIONS**

INTERFACING OPTIONS	CONNECTIONS	
CML	Connect VTD0, VTD0, VTD1, VTD1, VTSEL to V <sub>CC</sub>	
LVDS	Connect VTD0, VTD0 together for D0 input. Connect VTD1, VTD1 together for D0 input. Leave VTSEL open for SEL input.	
AC-COUPLED	Bias VTD0, VTD0, VTSEL and VTD1, VTD1 Inputs within (V <sub>CMR</sub> ) Common Mode Range	
RSECL, LVPECL	Standard ECL Termination Techniques. See AND8020/D.	
LVTTL, LVCMOS	An external voltage should be applied to the unused complementary differential input. Nominal voltage 1.5 V for LVTTL and $V_{\rm CC}/2$ for LVCMOS inputs.	

# **Application Information**

All inputs can accept PECL, CML, and LVDS signal levels. The input voltage can range from  $V_{CC}$  to 1.2 V.

Examples interfaces are illustrated below in a 50  $\Omega$  environment (Z = 50  $\Omega$ ).

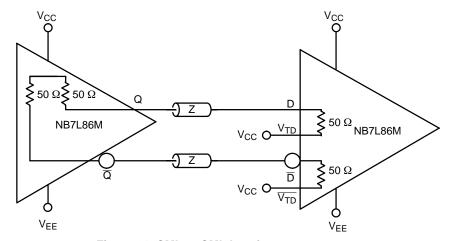


Figure 21. CML to CML Interface

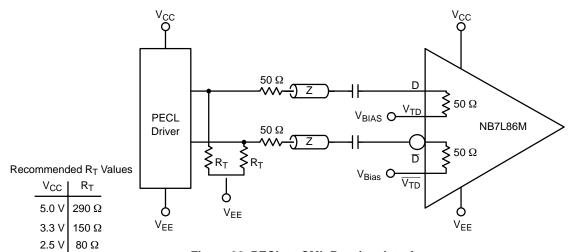


Figure 22. PECL to CML Receiver Interface

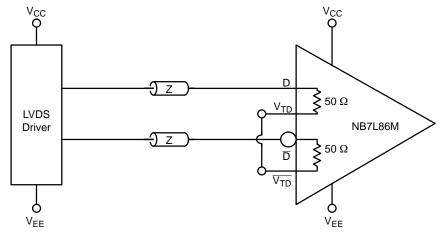


Figure 23. LVDS to CML Receiver Interface

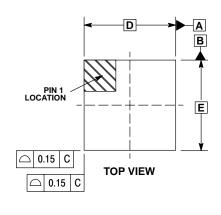
# **ORDERING INFORMATION**

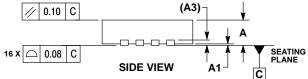
Device	Package	Shipping <sup>†</sup>
NB7L86MMN	QFN-16	123 Units/Rail
NB7L86MMNR2	QFN-16	3000 Tape & Reel
NB7L86MMNG	QFN-16 (Pb-Free)	123 Units/Rail
NB7L86MMNR2G	QFN-16 (Pb-Free)	3000 Tape & Reel

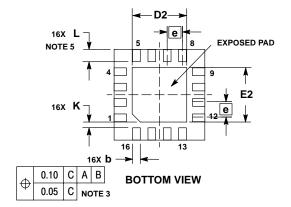
<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

## PACKAGE DIMENSIONS

## 16 PIN QFN **MN SUFFIX** CASE 485G-01 ISSUE B







#### NOTES:

- DIMENSIONING AND TOLERANCING PER
- ASME Y14.5M, 1994. CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN
- 125 AND 0.30 MM FROM TERMINAL.
  COPLANARITY APPLIES TO THE EXPOSED
  PAD AS WELL AS THE TERMINALS.
  L<sub>max</sub> CONDITION CAN NOT VIOLATE 0.2 MM
  MINIMUM SPACING BETWEEN LEAD TIP AND FLAG

	MILLIMETERS					
DIM	MIN	MAX				
Α	0.80	1.00				
A1	0.00	0.05				
А3	0.20	REF				
b	0.18	0.30				
D	3.00	BSC				
D2	1.65	1.85				
Е	3.00	BSC				
E2	1.65	1.85				
е	0.50 BSC					
K	0.20					
Ĺ	0.30	0.50				

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